

- 3-State Outputs Drive Bus Lines or Buffer-Memory Address Registers
- Package Options Include Plastic Small-Outline (DW) Packages and Standard Plastic (N) 300-mil DIPs

description

This octal buffer and line driver is designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

The 25- Ω resistors in the lower output circuit reduce ringing and eliminate the need for external resistors.

The SN74F2244 is characterized for operation from 0°C to 70°C.

DW OR N PACKAGE (TOP VIEW)

1OE	1	20	V _{CC}
1A1	2	19	2OE
2Y4	3	18	1Y1
1A2	4	17	2A4
2Y3	5	16	1Y2
1A3	6	15	2A3
2Y2	7	14	1Y3
1A4	8	13	2A2
2Y1	9	12	1Y4
GND	10	11	2A1

FUNCTION TABLE (each buffer)

INPUTS		OUTPUT
\overline{OE}	A	Y
L	H	H
L	L	L
H	X	Z

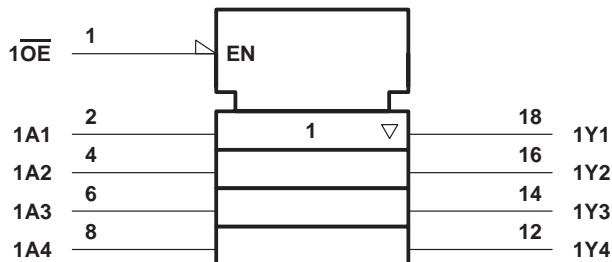


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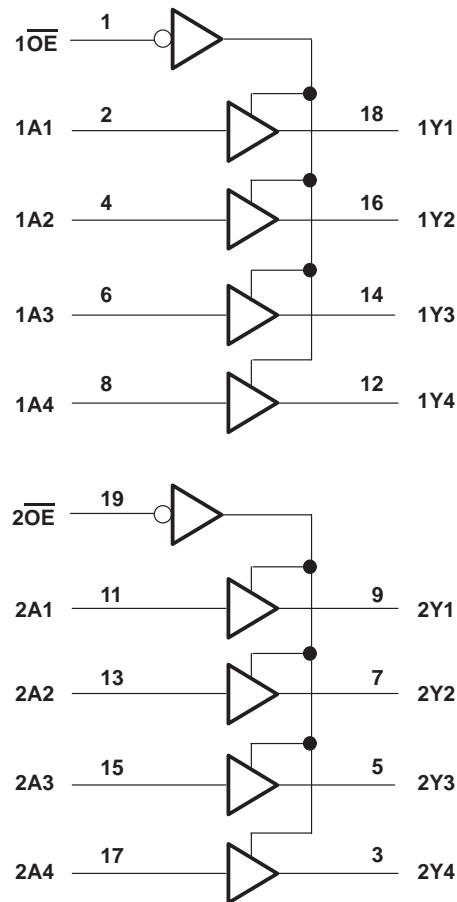
SN74F2244
25- Ω OCTAL BUFFER/DRIVER
WITH 3-STATE OUTPUTS

SDFS095B – NOVEMBER 1993 – REVISED JANUARY 1996

logic symbol†



logic diagram (positive logic)



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V_{CC}	-0.5 V to 7 V
Input voltage range, V_I (see Note 1)	-1.2 V to 7 V
Input current range, I_I	-30 mA to 5 mA
Voltage range applied to any output in the disabled or power-off state, V_O	-0.5 V to 5.5 V
Voltage range applied to any output in the high state, V_O	-0.5 V to V_{CC}
Current into any output in the low state, I_O	30 mA
Operating free-air temperature range, T_A	0°C to 70°C
Storage temperature range, T_{stg}	-65°C to 150°C

‡ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input voltage ratings may be exceeded if the input current ratings are observed.

recommended operating conditions

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.5	5	5.5	V
V_{IH}	High-level input voltage		2		V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
I_{OH}	High-level output current			-15	mA
I_{OL}	Low-level output current			12	mA
T_A	Operating free-air temperature	0	70		°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]		MIN	TYP [†]	MAX	UNIT
V_{IK}	$V_{CC} = 4.5$ V,	$I_I = -18$ mA			-1.2	V
V_{OH}	$V_{CC} = 4.5$ V,	$I_{OH} = -3$ mA	2.4	2.8		V
	$V_{CC} = 4.5$ V	$I_{OH} = -15$ mA	2	2.3		
	$V_{CC} = 4.75$ V,	$I_{OH} = -3$ mA		2.7		
V_{OL}	$V_{CC} = 4.5$ V,	$I_{OL} = 1$ mA	0.2	0.5		V
	$V_{CC} = 4.5$ V,	$I_{OL} = 12$ mA	0.5	0.75		
I_I	$V_{CC} = 5.5$ V,	$V_I = 0.5$ V		0.1		mA
I_{OZH}	$V_{CC} = 5.5$ V,	$V_O = 7$ V		50		μA
I_{OZL}	$V_{CC} = 5.5$ V,	$V_O = 2.7$ V		-50		μA
I_{IH}	$V_{CC} = 5.5$ V,	$V_I = 2.7$ V		20		μA
I_{IL}	Any \overline{OE} input	$V_{CC} = 5.5$ V,	$V_I = 0.5$ V	-1		mA
	Any A input			-1.6		
$I_{OS†}$	$V_{CC} = 5.5$ V,	$V_O = 0$	-100	-225		mA
I_{CC}	$V_{CC} = 5.5$ V, Outputs open	Outputs high	40	60		mA
		Outputs low	60	90		
		Outputs disabled	60	90		

[†] All typical values are at $V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$.

[‡] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

switching characteristics (see Figure 1)

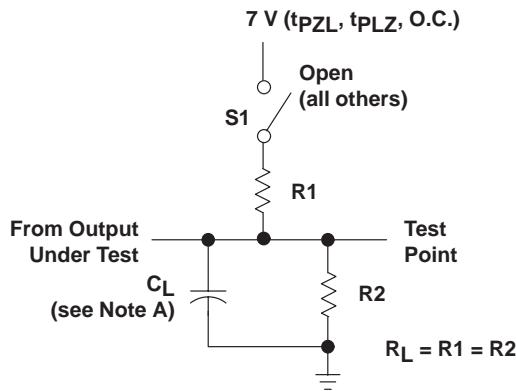
PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 5$ V, $C_L = 50$ pF, $R_1 = 500$ Ω, $R_2 = 500$ Ω, $T_A = 25^\circ\text{C}$	$V_{CC} = 4.5$ V TO 5.5 V, $C_L = 50$ pF, $R_1 = 500$ Ω, $R_2 = 500$ Ω, $T_A = \text{MIN TO MAX}^§$	UNIT
			MIN	MAX	
t_{PLH}	A	Y	1.5	7	ns
			2.5	8	
t_{PHL}	\overline{OE}	Y	1.5	9	ns
			2.5	11.5	
t_{PZH}	OE	Y	1.5	9	ns
			1.5	8.5	
t_{PZL}	OE	Y	1	9.5	ns
			2.5	12	
t_{PHZ}	OE	Y	1	9.5	ns
			1.5	9.5	
t_{PLZ}	OE	Y	1.5	9.5	
			1.5	9.5	

[§] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

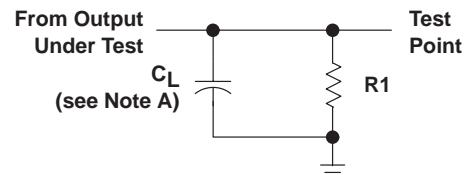
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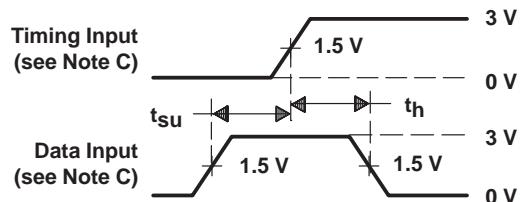
PARAMETER MEASUREMENT INFORMATION



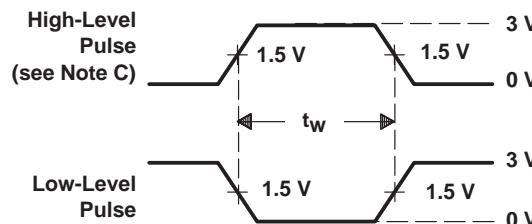
LOAD CIRCUIT FOR
 3-STATE AND OPEN-COLLECTOR OUTPUTS



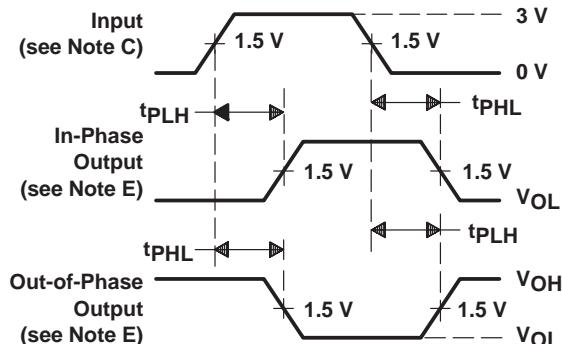
LOAD CIRCUIT FOR
 TOTEM-POLE OUTPUTS



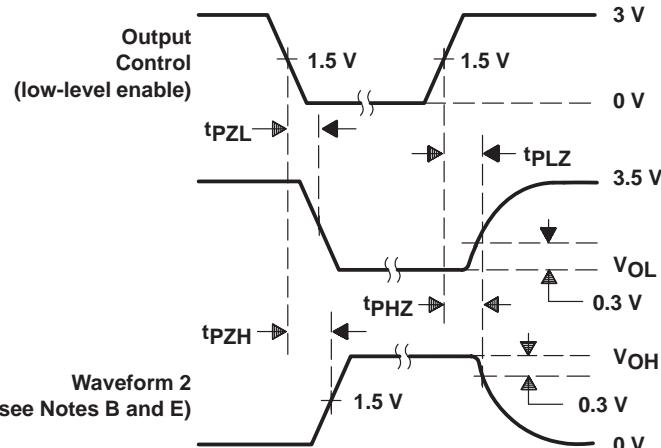
VOLTAGE WAVEFORMS
 SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
 PULSE DURATION



VOLTAGE WAVEFORMS
 PROPAGATION DELAY TIMES (see Note D)



VOLTAGE WAVEFORMS
 ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

NOTES: A. C_L includes probe and jig capacitance.
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $t_r = t_f \leq 2.5$ ns, duty cycle = 50%.
 D. When measuring propagation delay times of 3-state outputs, switch S1 is open.
 E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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